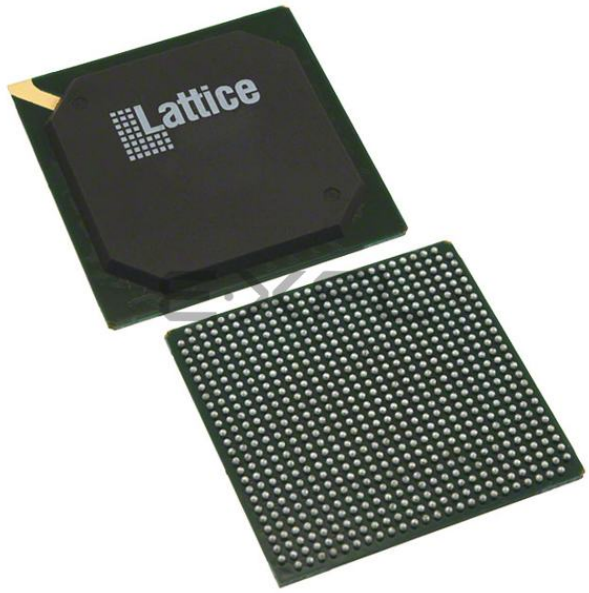
Lattice Semiconductor Corporation - LFE3-95E-8FN672C Datasheet



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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

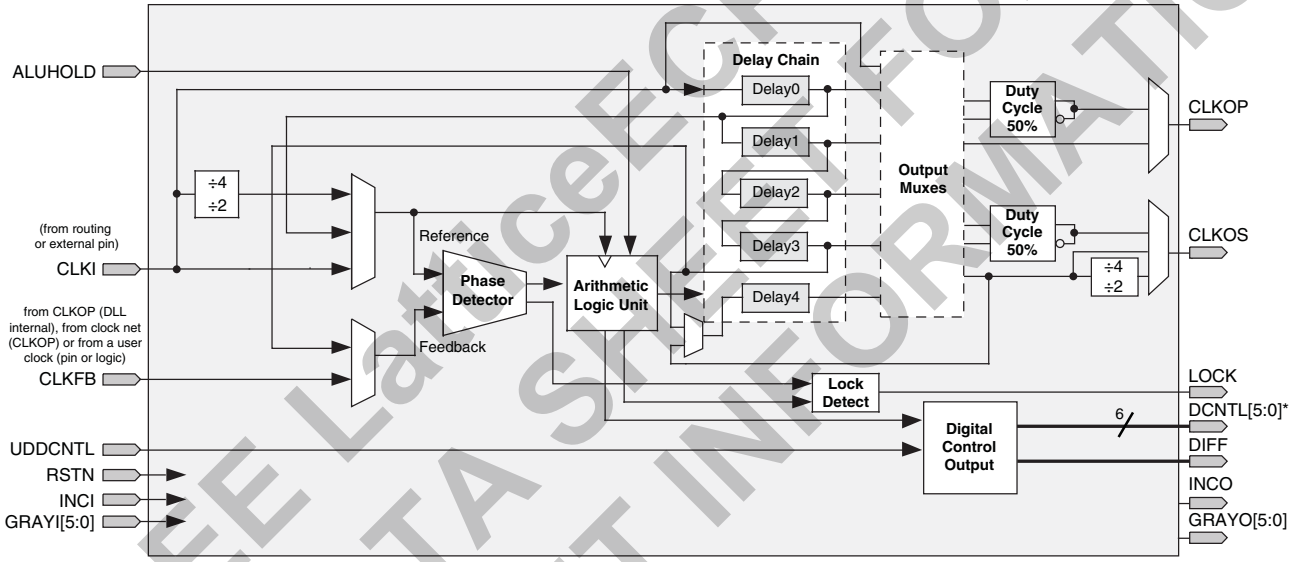
Details	
Product Status	Obsolete
Number of LABs/CLBs	11500
Number of Logic Elements/Cells	92000
Total RAM Bits	4526080
Number of I/O	380
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	672-BBGA
Supplier Device Package	672-FPBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lfe3-95e-8fn672c

chain in order to better match the reference and feedback signals. This digital code from the ALU is also transmitted via the Digital Control bus (DCNTL) bus to its associated Slave Delay lines (two per DLL). The ALUHOLD input allows the user to suspend the ALU output at its current value. The UDDCNTL signal allows the user to latch the current value on the DCNTL bus.

The DLL has two clock outputs, CLKOP and CLKOS. These outputs can individually select one of the outputs from the tapped delay line. The CLKOS has optional fine delay shift and divider blocks to allow this output to be further modified, if required. The fine delay shift block allows the CLKOS output to phase shifted a further 45, 22.5 or 11.25 degrees relative to its normal position. Both the CLKOS and CLKOP outputs are available with optional duty cycle correction. Divide by two and divide by four frequencies are available at CLKOS. The LOCK output signal is asserted when the DLL is locked. Figure 2-5 shows the DLL block diagram and Table 2-5 provides a description of the DLL inputs and outputs.

The user can configure the DLL for many common functions such as time reference delay mode and clock injection removal mode. Lattice provides primitives in its design tools for these functions.

Figure 2-5. Delay Locked Loop Diagram (DLL)



* This signal is not user accessible. This can only be used to feed the slave delay line.

Table 2-5. DLL Signals

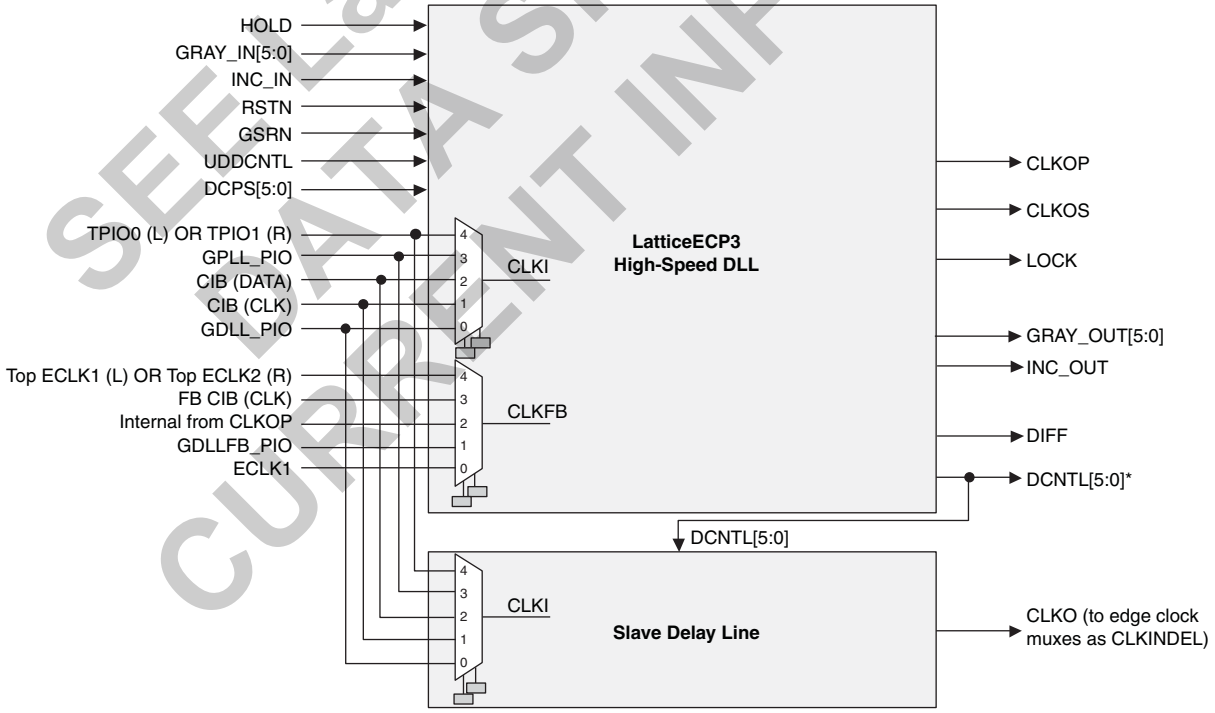
Signal	I/O	Description
CLKI	I	Clock input from external pin or routing
CLKFB	I	DLL feed input from DLL output, clock net, routing or external pin
RSTN	I	Active low synchronous reset
ALUHOLD	I	Active high freezes the ALU
UDDCNTL	I	Synchronous enable signal (hold high for two cycles) from routing
CLKOP	O	The primary clock output
CLKOS	O	The secondary clock output with fine delay shift and/or division by 2 or by 4
LOCK	O	Active high phase lock indicator
INCI	I	Incremental indicator from another DLL via CIB.
GRAYI[5:0]	I	Gray-coded digital control bus from another DLL in time reference mode.
DIFF	O	Difference indicator when DCNTL is difference than the internal setting and update is needed.
INCO	O	Incremental indicator to other DLLs via CIB.
GRAYO[5:0]	O	Gray-coded digital control bus to other DLLs via CIB

LatticeECP3 devices have two general DLLs and four Slave Delay lines, two per DLL. The DLLs are in the lowest EBR row and located adjacent to the EBR. Each DLL replaces one EBR block. One Slave Delay line is placed adjacent to the DLL and the duplicate Slave Delay line (in Figure 2-6) for the DLL is placed in the I/O ring between Banks 6 and 7 and Banks 2 and 3.

The outputs from the DLL and Slave Delay lines are fed to the clock distribution network.

For more information, please see TN1178, LatticeECP3 sysCLOCK PLL/DLL Design and Usage Guide.

Figure 2-6. Top-Level Block Diagram, High-Speed DLL and Slave Delay Line



* This signal is not user accessible. It can only be used to feed the slave delay line.

PLL/DLL Cascading

LatticeECP3 devices have been designed to allow certain combinations of PLL and DLL cascading. The allowable combinations are:

- PLL to PLL supported
- PLL to DLL supported

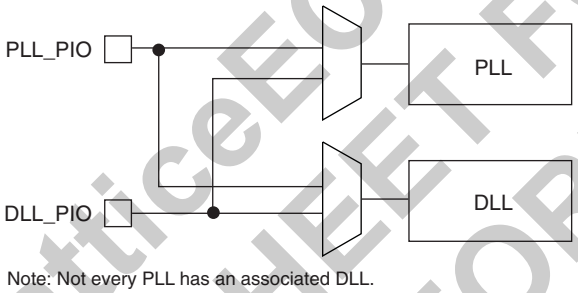
The DLLs in the LatticeECP3 are used to shift the clock in relation to the data for source synchronous inputs. PLLs are used for frequency synthesis and clock generation for source synchronous interfaces. Cascading PLL and DLL blocks allows applications to utilize the unique benefits of both DLLs and PLLs.

For further information about the DLL, please see the list of technical documentation at the end of this data sheet.

PLL/DLL PIO Input Pin Connections

All LatticeECP3 devices contains two DLLs and up to ten PLLs, arranged in quadrants. If a PLL and a DLL are next to each other, they share input pins as shown in the Figure 2-7.

Figure 2-7. Sharing of PIO Pins by PLLs and DLLs in LatticeECP3 Devices



Note: Not every PLL has an associated DLL.

Clock Dividers

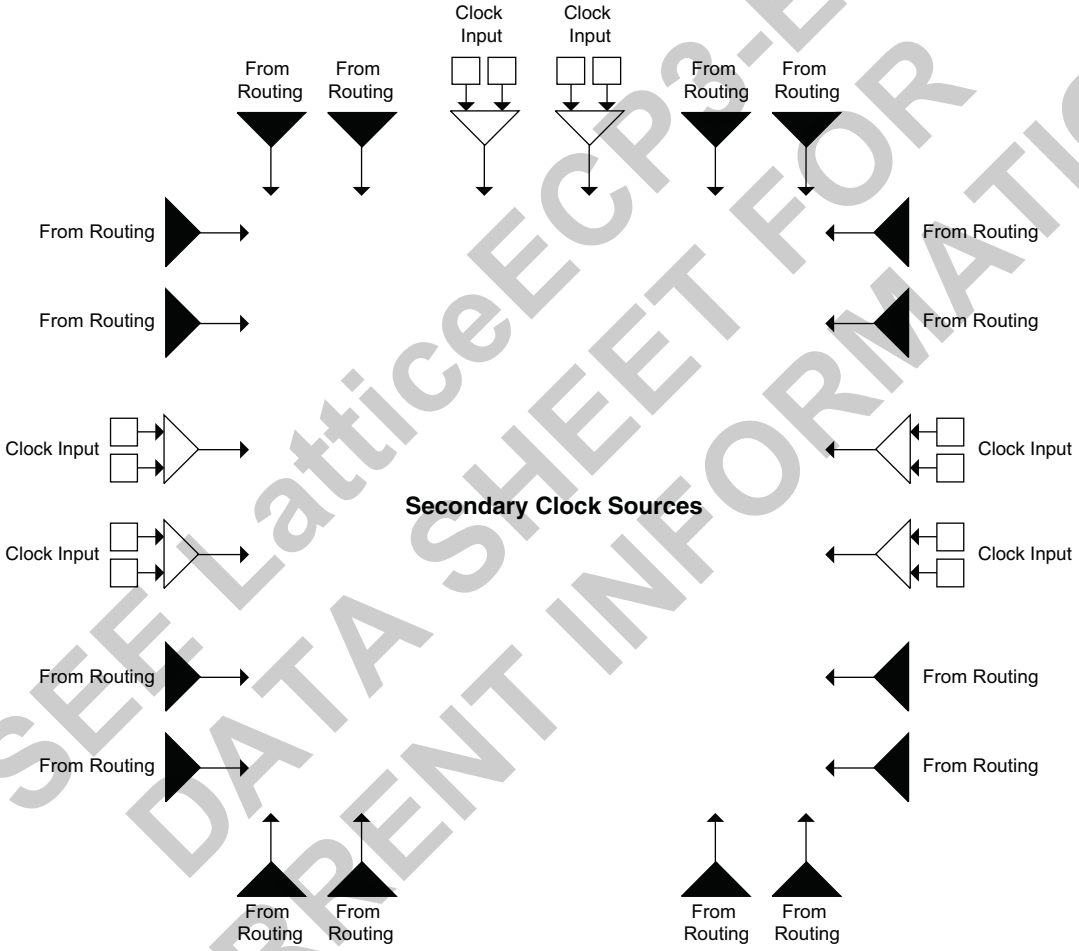
LatticeECP3 devices have two clock dividers, one on the left side and one on the right side of the device. These are intended to generate a slower-speed system clock from a high-speed edge clock. The block operates in a ÷2, ÷4 or ÷8 mode and maintains a known phase relationship between the divided down clock and the high-speed clock based on the release of its reset signal. The clock dividers can be fed from selected PLL/DLL outputs, the Slave Delay lines, routing or from an external clock input. The clock divider outputs serve as primary clock sources and feed into the clock distribution network. The Reset (RST) control signal resets input and asynchronously forces all outputs to low. The RELEASE signal releases outputs synchronously to the input clock. For further information on clock dividers, please see TN1178, LatticeECP3 sysCLOCK PLL/DLL Design and Usage Guide. Figure 2-8 shows the clock divider connections.

Secondary Clock/Control Sources

LatticeECP3 devices derive eight secondary clock sources (SC0 through SC7) from six dedicated clock input pads and the rest from routing. Figure 2-14 shows the secondary clock sources. All eight secondary clock sources are defined as inputs to a per-region mux SC0-SC7. SC0-SC3 are primary for control signals (CE and/or LSR), and SC4-SC7 are for clock and high fanout data.

In an actual implementation, there is some overlap to maximize routability. In addition to SC0-SC3, SC7 is also an input to the control signals (LSR or CE). SC0-SC2 are also inputs to clocks along with SC4-SC7. High fanout logic signals (LUT inputs) will utilize the X2 and X0 switches where SC0-SC7 are inputs to X2 switches, and SC4-SC7 are inputs to X0 switches. Note that through X0 switches, SC4-SC7 can also access control signals CE/LSR.

Figure 2-14. Secondary Clock Sources



Note: Clock inputs can be configured in differential or single-ended mode.

Secondary Clock/Control Routing

Global secondary clock is a secondary clock that is distributed to all regions. The purpose of the secondary clock routing is to distribute the secondary clock sources to the secondary clock regions. Secondary clocks in the LatticeECP3 devices are region-based resources. Certain EBR rows and special vertical routing channels bind the secondary clock regions. This special vertical routing channel aligns with either the left edge of the center DSP slice in the DSP row or the center of the DSP row. Figure 2-15 shows this special vertical routing channel and the 20 secondary clock regions for the LatticeECP3 family of devices. All devices in the LatticeECP3 family have eight

Two adjacent PIOs can be joined to provide a differential I/O pair (labeled as "T" and "C") as shown in Figure 2-32. The PAD Labels "T" and "C" distinguish the two PIOs. Approximately 50% of the PIO pairs on the left and right edges of the device can be configured as true LVDS outputs. All I/O pairs can operate as LVDS inputs.

Table 2-11. PIO Signal List

Name	Type	Description
INDD	Input Data	Register bypassed input. This is not the same port as INCK.
IPA, INA, IPB, INB	Input Data	Ports to core for input data
OPOSA, ONEGA[1], OPOSB, ONEGB[1]	Output Data	Output signals from core. An exception is the ONEGB port, used for tristate logic at the DQS pad.
CE	PIO Control	Clock enables for input and output block flip-flops.
SCLK	PIO Control	System Clock (PCLK) for input and output/TS blocks. Connected from clock ISB.
LSR	PIO Control	Local Set/Reset
ECLK1, ECLK2	PIO Control	Edge clock sources. Entire PIO selects one of two sources using mux.
ECLKDQSR[1]	Read Control	From DQS_STROBE, shifted strobe for memory interfaces only.
DDRCLKPOL[1]	Read Control	Ensures transfer from DQS domain to SCLK domain.
DDRLAT[1]	Read Control	Used to guarantee INDDRX2 gearing by selectively enabling a D-Flip-Flop in datapath.
DEL[3:0]	Read Control	Dynamic input delay control bits.
INCK	To Clock Distribution and PLL	PIO treated as clock PIO, path to distribute to primary clocks and PLL.
TS	Tristate Data	Tristate signal from core (SDR)
DQCLK0[1], DQCLK1[1]	Write Control	Two clocks edges, 90 degrees out of phase, used in output gearing.
DQSW[2]	Write Control	Used for output and tristate logic at DQS only.
DYNDEL[7:0]	Write Control	Shifting of write clocks for specific DQS group, using 6:0 each step is approximately 25ps, 128 steps. Bit 7 is an invert (timing depends on input frequency). There is also a static control for this 8-bit setting, enabled with a memory cell.
DCNTL[6:0]	PIO Control	Original delay code from DDR DLL
DATAVALID[1]	Output Data	Status flag from DATAVALID logic, used to indicate when input data is captured in IOLOGIC and valid to core.
READ	For DQS_Strobe	Read signal for DDR memory interface
DQSI	For DQS_Strobe	Unshifted DQS strobe from input pad
PRMBDET	For DQS_Strobe	DQSI biased to go high when DQSI is tristate, goes to input logic block as well as core logic.
GSRN	Control from routing	Global Set/Reset

1. Signals available on left/right/top edges only.
2. Selected PIO.

PIO

The PIO contains four blocks: an input register block, output register block, tristate register block and a control logic block. These blocks contain registers for operating in a variety of modes along with the necessary clock and selection logic.

Input Register Block

The input register blocks for the PIOs, in the left, right and top edges, contain delay elements and registers that can be used to condition high-speed interface signals, such as DDR memory interfaces and source synchronous interfaces, before they are passed to the device core. Figure 2-33 shows the input register block for the left, right and top edges. The input register block for the bottom edge contains one element to register the input signal and no DDR registers. The following description applies to the input register block for PIOs in the left, right and top edges only.

To accomplish write leveling in DDR3, each DQS group has a slightly different delay that is set by DYN DELAY[7:0] in the DQS Write Control logic block. The DYN DELAY can set 128 possible delay step settings. In addition, the most significant bit will invert the clock for a 180-degree shift of the incoming clock.

LatticeECP3 input and output registers can also support DDR gearing that is used to receive and transmit the high speed DDR data from and to the DDR3 Memory.

LatticeECP3 supports the 1.5V SSTL I/O standard required for the DDR3 memory interface. In addition, it supports on-chip termination to VTT on the DDR3 memory input pins. For more information, refer to the sysIO section of this data sheet.

Please see TN1180, LatticeECP3 High-Speed I/O Interface for more information on DDR Memory interface implementation in LatticeECP3.

sysI/O Buffer

Each I/O is associated with a flexible buffer referred to as a sysI/O buffer. These buffers are arranged around the periphery of the device in groups referred to as banks. The sysI/O buffers allow users to implement the wide variety of standards that are found in today's systems including LVDS, BLVDS, HSTL, SSTL Class I & II, LVCMOS, LVTTL, LVPECL, PCI.

sysI/O Buffer Banks

LatticeECP3 devices have six sysI/O buffer banks: six banks for user I/Os arranged two per side. The banks on the bottom side are wraparounds of the banks on the lower right and left sides. The seventh sysI/O buffer bank (Configuration Bank) is located adjacent to Bank 2 and has dedicated/shared I/Os for configuration. When a shared pin is not used for configuration it is available as a user I/O. Each bank is capable of supporting multiple I/O standards. Each sysI/O bank has its own I/O supply voltage (V_{CCIO}). In addition, each bank, except the Configuration Bank, has voltage references, V_{REF1} and V_{REF2}, which allow it to be completely independent from the others. The Configuration Bank top side shares V_{REF1} and V_{REF2} from sysI/O bank 1 and right side shares V_{REF1} and V_{REF2} from sysI/O bank 2. Figure 2-38 shows the seven banks and their associated supplies.

In LatticeECP3 devices, single-ended output buffers and ratioed input buffers (LVTTL, LVCMOS and PCI) are powered using V_{CCIO}. LVTTL, LVCMOS33, LVCMOS25 and LVCMOS12 can also be set as fixed threshold inputs independent of V_{CCIO}.

Each bank can support up to two separate V_{REF} voltages, V_{REF1} and V_{REF2}, that set the threshold for the referenced input buffers. Some dedicated I/O pins in a bank can be configured to be a reference voltage supply pin. Each I/O is individually configurable based on the bank's supply and reference voltages.

The ispLEVER design tools from Lattice support all modes of the PCS. Most modes are dedicated to applications associated with a specific industry standard data protocol. Other more general purpose modes allow users to define their own operation. With ispLEVER, the user can define the mode for each quad in a design.

Popular standards such as 10Gb Ethernet, x4 PCI Express and 4x Serial RapidIO can be implemented using IP (available through Lattice), a single quad (Four SERDES channels and PCS) and some additional logic from the core.

The LatticeECP3 family also supports a wide range of primary and secondary protocols. Within the same quad, the LatticeECP3 family can support mixed protocols with semi-independent clocking as long as the required clock frequencies are integer x1, x2, or x11 multiples of each other. Table 2-15 lists the allowable combination of primary and secondary protocol combinations.

Flexible Quad SERDES Architecture

The LatticeECP3 family SERDES architecture is a quad-based architecture. For most SERDES settings and standards, the whole quad (consisting of four SERDES) is treated as a unit. This helps in silicon area savings, better utilization and overall lower cost.

However, for some specific standards, the LatticeECP3 quad architecture provides flexibility; more than one standard can be supported within the same quad.

Table 2-15 shows the standards can be mixed and matched within the same quad. In general, the SERDES standards whose nominal data rates are either the same or a defined subset of each other, can be supported within the same quad. In Table 2-15, the Primary Protocol column refers to the standard that determines the reference clock and PLL settings. The Secondary Protocol column shows the other standard that can be supported within the same quad.

Furthermore, Table 2-15 also implies that more than two standards in the same quad can be supported, as long as they conform to the data rate and reference clock requirements. For example, a quad may contain PCI Express 1.1, SGMII, Serial RapidIO Type I and Serial RapidIO Type II, all in the same quad.

Table 2-15. LatticeECP3 Primary and Secondary Protocol Support

Primary Protocol	Secondary Protocol
PCI Express 1.1	SGMII
PCI Express 1.1	Gigabit Ethernet
PCI Express 1.1	Serial RapidIO Type I
PCI Express 1.1	Serial RapidIO Type II
Serial RapidIO Type I	SGMII
Serial RapidIO Type I	Gigabit Ethernet
Serial RapidIO Type II	SGMII
Serial RapidIO Type II	Gigabit Ethernet
Serial RapidIO Type II	Serial RapidIO Type I
CPRI-3	CPRI-2 and CPRI-1
3G-SDI	HD-SDI and SD-SDI

For further information on SERDES, please see TN1176, LatticeECP3 SERDES/PCS Usage Guide.

IEEE 1149.1-Compliant Boundary Scan Testability

All LatticeECP3 devices have boundary scan cells that are accessed through an IEEE 1149.1 compliant Test Access Port (TAP). This allows functional testing of the circuit board on which the device is mounted through a serial scan path that can access all critical logic nodes. Internal registers are linked internally, allowing test data to be shifted in and loaded directly onto test nodes, or test data to be captured and shifted out for verification. The test

Typical Building Block Function Performance

Pin-to-Pin Performance (LVCMOS25 12mA Drive)[1, 2]

Function	-8 Timing	Units
Basic Functions		
16-bit Decoder	4.7	ns
32-bit Decoder	4.7	ns
64-bit Decoder	5.7	ns
4:1 MUX	4.1	ns
8:1 MUX	4.3	ns
16:1 MUX	4.7	ns
32:1 MUX	4.8	ns

1. These functions were generated using the ispLEVER design tool. Exact performance may vary with device and tool version. The tool uses internal parameters that have been characterized but are not tested on every device.
2. Commercial timing numbers are shown. Industrial numbers are typically slower and can be extracted from the ispLEVER software.

Register-to-Register Performance[1, 2]

Function	-8 Timing	Units
Basic Functions		
16-bit Decoder	500	MHz
32-bit Decoder	500	MHz
64-bit Decoder	475	MHz
4:1 MUX	500	MHz
8:1 MUX	500	MHz
16:1 MUX	500	MHz
32:1 MUX	445	MHz
8-bit adder	500	MHz
16-bit adder	500	MHz
64-bit adder	305	MHz
16-bit counter	500	MHz
32-bit counter	460	MHz
64-bit counter	320	MHz
64-bit accumulator	315	MHz
Embedded Memory Functions		
512x36 Single Port RAM, EBR Output Registers	340	MHz
1024x18 True-Dual Port RAM (Write Through or Normal, EBR Output Registers)	340	MHz
1024x18 True-Dual Port RAM (Read-Before-Write, EBR Output Registers; EA devices only)	130	MHz
1024x18 True-Dual Port RAM (Write Through or Normal, PLC Output Registers)	245	MHz
Distributed Memory Functions		
16x4 Pseudo-Dual Port RAM (One PFU)	500	MHz
32x4 Pseudo-Dual Port RAM	500	MHz
64x8 Pseudo-Dual Port RAM	380	MHz
DSP Function		
18x18 Multiplier (All Registers)	400	MHz
9x9 Multiplier (All Registers)	400	MHz
36x36 Multiply (All Registers)	245	MHz

Register-to-Register Performance[1, 2]

Function	-8 Timing	Units
18x18 Multiply/Accumulate (Input & Output Registers)	200	MHz
18x18 Multiply-Add/Sub (All Registers)	400	MHz
DSP IP Functions		
16-Tap Fully-Parallel FIR Filter		MHz
1024-pt, Radix 4, Decimation in Frequency FFT		MHz
8X8 Matrix Multiplication		MHz

1. These timing numbers were generated using ispLEVER tool. Exact performance may vary with device and tool version. The tool uses internal parameters that have been characterized but are not tested on every device.
2. Commercial timing numbers are shown. Industrial numbers are typically slower and can be extracted from the ispLEVER software.

Derating Timing Tables

Logic timing provided in the following sections of this data sheet and the ispLEVER design tools are worst case numbers in the operating range. Actual delays at nominal temperature and voltage for best case process, can be much better than the values given in the tables. The ispLEVER design tool can provide logic timing numbers at a particular temperature and voltage.

LatticeECP3 External Switching Characteristics (Continued)[1, 2]

Over Recommended Commercial Operating Conditions

Parameter	Description	Device	-8		-7		-6		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
$t_{DVECLKGDDR}$	Data Hold After CLK	ECP3-70E/95E	0.765	—	0.765	—	0.765	—	UI
f_{MAX_GDDR}	DDR/DDRX2 Clock Frequency[8]	ECP3-70E/95E	—	500	—	420	—	375	MHz
Generic DDRX2 Inputs with Clock and Data (<10 Bits Wide) Centered at Pin (GDDRX2_RX.DQS.Centered) using DQS Pin for Clock Input									
Left and Right Sides									
t_{SUGDDR}	Data Setup Before CLK	ECP3-150EA		—		—		—	ns
t_{HGDDR}	Data Hold After CLK	ECP3-150EA		—		—		—	ns
f_{MAX_GDDR}	DDRX2 Clock Frequency	ECP3-150EA	—		—		—		ns
Generic DDRX2 Inputs with Clock and Data (<10 Bits Side) Aligned at Pin (GDDRX2_RX.DQS.Aligned) Using DQS Pin for Clock Input									
Left and Right Sides									
$t_{DVACLKGDDR}$	Data Setup Before CLK (Left and Right Side)	ECP3-150EA	—		—		—		
$t_{DVECLKGDDR}$	Data Hold After CLK (Left and Right Side)	ECP3-150EA		—		—		—	
f_{MAX_GDDR}	DDRX2 Clock Frequency (Left and Right Side)	ECP3-150EA	—		—		—		
Generic DDRX1 Output with Clock and Data (>10 Bits Wide) Centered at Pin (GDDRX1_TX.SCLK.Centered)									
Left, Right and Top Sides									
$t_{DVBGDDR}$	Data Valid Before CLK	ECP3-150EA		—		—		—	
$t_{DVAGDDR}$	Data Valid After CLK	ECP3-150EA		—		—		—	
f_{MAX_GDDR}	DDRX1 Clock Frequency	ECP3-150EA	—		—		—		
Generic DDRX1 Outputs with clock in the center of data window, with PLL 90-degree shifted clock ouput (GDDRX1_TX.ECLK.Centered)									
$t_{DIBGDDR}$	Data Invalid Before CLK	ECP3-70E/95E	670	—	670	—	670	—	ps
$t_{DIAGDDR}$	Data Invalid After CLK	ECP3-70E/95E	670	—	670	—	670	—	ps
fMAX_GDDR	DDRX1 Clock Frequency	ECP3-70E/95E	—	250	—	250	—	250	MHz
Generic DDRX1 Output with Clock and Data (> 10 Bits Wide) Aligned at Pin (GDDRX1_TX.SCLK.Aligned)									
Left, Right and Top Sides									
$t_{DIBGDDR}$	Data Hold After CLK	ECP3-150EA	—		—		—		
$t_{DIAGDDR}$	Data Setup Before CLK	ECP3-150EA	—		—		—		
f_{MAX_GDDR}	DDRX1 Clock Frequency	ECP3-150EA	—		—		—		
Generic DDRX1 Outputs with clock and data edge aligned, without PLL									
$t_{DIBGDDR}$	Data Invalid Before CLK	ECP3-70E/95E	—	330	—	330	—	330	ps
$t_{DIAGDDR}$	Data Invalid After CLK	ECP3-70E/95E	—	330	—	330	—	330	ps
f_{MAX_GDDR}	DDRX1 Clock Frequency	ECP3-70E/95E	—	250	—	250	—	250	MHz
Generic DDRX1 Output with Clock and Data (<10 Bits Wide) Centered at Pin (GDDRX1_TX.DQS.Centered)									
Left, Right and Top Sides									
$t_{DVBGDDR}$	Data Valid Before CLK	ECP3-150EA	—		—		—		
$t_{DVAGDDR}$	Data Valid After CLK	ECP3-150EA	—		—		—		
f_{MAX_GDDR}	DDRX1 Clock Frequency	ECP3-150EA	—		—		—		

LatticeECP3 External Switching Characteristics (Continued)[1, 2]

Over Recommended Commercial Operating Conditions

Parameter	Description	Device	-8		-7		-6		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
Generic DDRX2 Output with Clock and Data (> 10 Bits Wide) Aligned at Pin (GDDRX2_TX.ECLK.Aligned)									
Left and Right Sides									
$t_{DIBGDDR}$	Data Setup Before CLK	ECP3-150EA	—		—		—		ps
$t_{DIAGDDR}$	Data Hold After CLK	ECP3-150EA	—		—		—		ps
f_{MAX_GDDR}	DDRX2 Clock Frequency	ECP3-150EA	—		—		—		MHz
Generic DDRX2 Outputs with Clock and Data Edges Aligned, Without PLL 90-degree shifted clock output[5] (GDDRX2_TX.Aligned)									
$t_{DIBGDDR}$	Data Invalid Before Clock	ECP3-70E/95E	—	200	—	225	—	250	ps
$t_{DIAGDDR}$	Data Invalid After Clock	ECP3-70E/95E	—	200	—	225	—	250	ps
f_{MAX_GDDR}	DDR/DDRX2 Clock Frequency[8]	ECP3-70E/95E	—	500	—	420	—	375	MHz
Generic DDRX2 Output with Clock and Data (> 10 Bits Wide) Centered at Pin Using DQSDLL (GDDRX2_TX.DQS-DLL.Centered)									
Left and Right Sides									
$t_{DVBGDDR}$	Data Valid Before CLK	ECP3-150EA		—		—		—	ns
$t_{DVAGDDR}$	Data Valid After CLK	ECP3-150EA		—		—		—	ns
f_{MAX_GDDR}	DDRX2 Clock Frequency	ECP3-150EA	—		—		—		ns
Generic DDRX2 Output with Clock and Data (> 10 Bits Wide) Centered at Pin Using PLL (GDDRX2_TX.PLL.Centered)									
Left and Right Sides									
$t_{DVBGDDR}$	Data Valid Before CLK	ECP3-150EA		—		—		—	ns
$t_{DVAGDDR}$	Data Valid After CLK	ECP3-150EA		—		—		—	ns
f_{MAX_GDDR}	DDRX2 Clock Frequency	ECP3-150EA	—		—		—		ns
Generic DDRX2 Outputs with Clock Edge in the Center of Data Window, with PLL 90-degree Shifted Clock Output[6] (GDDRX2_TX.PLL.Centered)									
$t_{DVBGDDR}$	Data Valid Before CLK	ECP3-70E/95E	300	—	370	—	417	—	ps
$t_{DVAGDDR}$	Data Valid After CLK	ECP3-70E/95E	300	—	370	—	417	—	ps
f_{MAX_GDDR}	DDR/DDRX2 Clock Frequency[8]	ECP3-70E/95E	—	500	—	420	—	375	MHz

Parameter	Description	Device	-8		-7		-6		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
Memory Interface									
DDR/DDR2 SDRAM I/O Pin Parameters (Input Data are Strobe Edge Aligned, Output Strobe Edge is Data Centered)[4]									
t_{DVADQ}	Data Valid After DQS (DDR Read)	ECP3-150EA	—	0.225	—	0.225	—	0.225	UI
t_{DVEDQ}	Data Hold After DQS (DDR Read)	ECP3-150EA	0.64	—	0.64	—	0.64	—	UI
t_{DQVBS}	Data Valid Before DQS	ECP3-150EA	0.25	—	0.25	—	0.25	—	UI
t_{DQVAS}	Data Valid After DQS	ECP3-150EA	0.25	—	0.25	—	0.25	—	UI
f_{MAX_DDR}	DDR Clock Frequency	ECP3-150EA	95	200	95	200	95	166	MHz
f_{MAX_DDR2}	DDR2 clock frequency	ECP3-150EA	133	266	133	200	133	166	MHz
t_{DVADQ}	Data Valid After DQS (DDR Read)	ECP3-70E/95E	—	0.225	—	0.225	—	0.225	UI
t_{DVEDQ}	Data Hold After DQS (DDR Read)	ECP3-70E/95E	0.64	—	0.64	—	0.64	—	UI
t_{DQVBS}	Data Valid Before DQS	ECP3-70E/95E	0.25	—	0.25	—	0.25	—	UI
t_{DQVAS}	Data Valid After DQS	ECP3-70E/95E	0.25	—	0.25	—	0.25	—	UI
f_{MAX_DDR}	DDR Clock Frequency	ECP3-70E/95E	95	200	95	200	95	133	MHz

LatticeECP3 Family Timing Adders[1, 2, 3, 4, 5] (Continued)

Over Recommended Commercial Operating Conditions

Buffer Type	Description	-8	-7	-6	Units
LVCMOS15_4mA	LVCMOS 1.5 4mA drive, fast slew rate	0.09	0.10	0.10	ns
LVCMOS15_8mA	LVCMOS 1.5 8mA drive, fast slew rate	0.01	0.01	0.00	ns
LVCMOS12_2mA	LVCMOS 1.2 2mA drive, fast slew rate	0.08	0.08	0.08	ns
LVCMOS12_6mA	LVCMOS 1.2 6mA drive, fast slew rate	-0.02	-0.02	-0.02	ns
LVCMOS33_4mA	LVCMOS 3.3 4mA drive, slow slew rate	1.64	1.71	1.77	ns
LVCMOS33_8mA	LVCMOS 3.3 8mA drive, slow slew rate	1.39	1.45	1.51	ns
LVCMOS33_12mA	LVCMOS 3.3 12mA drive, slow slew rate	1.21	1.27	1.33	ns
LVCMOS33_16mA	LVCMOS 3.3 16mA drive, slow slew rate	1.43	1.49	1.55	ns
LVCMOS33_20mA	LVCMOS 3.3 20mA drive, slow slew rate	1.23	1.28	1.34	ns
LVCMOS25_4mA	LVCMOS 2.5 4mA drive, slow slew rate	1.66	1.70	1.74	ns
LVCMOS25_8mA	LVCMOS 2.5 8mA drive, slow slew rate	1.39	1.43	1.46	ns
LVCMOS25_12mA	LVCMOS 2.5 12mA drive, slow slew rate	1.20	1.24	1.28	ns
LVCMOS25_16mA	LVCMOS 2.5 16mA drive, slow slew rate	1.42	1.45	1.49	ns
LVCMOS25_20mA	LVCMOS 2.5 20mA drive, slow slew rate	1.22	1.26	1.29	ns
LVCMOS18_4mA	LVCMOS 1.8 4mA drive, slow slew rate	1.61	1.65	1.68	ns
LVCMOS18_8mA	LVCMOS 1.8 8mA drive, slow slew rate	1.32	1.36	1.39	ns
LVCMOS18_12mA	LVCMOS 1.8 12mA drive, slow slew rate	1.14	1.17	1.21	ns
LVCMOS18_16mA	LVCMOS 1.8 16mA drive, slow slew rate	1.35	1.38	1.42	ns
LVCMOS15_4mA	LVCMOS 1.5 4mA drive, slow slew rate	1.57	1.60	1.64	ns
LVCMOS15_8mA	LVCMOS 1.5 8mA drive, slow slew rate	0.01	0.01	0.00	ns
LVCMOS12_2mA	LVCMOS 1.2 2mA drive, slow slew rate	1.51	1.54	1.58	ns
LVCMOS12_6mA	LVCMOS 1.2 6mA drive, slow slew rate	-0.02	-0.02	-0.02	ns
PCI33	PCI, VCCIO = 3.0V	0.19	0.21	0.24	ns

1. Timing adders are characterized but not tested on every device.
2. LVCMOS timing measured with the load specified in Switching Test Condition table.
3. All other standards tested according to the appropriate specifications.
4. Not all I/O standards and drive strengths are supported for all banks. See the Architecture section of this data sheet for details.
5. Commercial timing numbers are shown. Industrial numbers are typically slower and can be extracted from the ispLEVER software.

Gigabit Ethernet/Serial Rapid I/O Type 1/SGMII Electrical and Timing Characteristics

AC and DC Characteristics

Table 3-17. Transmit

Symbol	Description	Test Conditions	Min.	Typ.	Max.	Units
T_{RF}	Differential rise/fall time	20%-80%	—	80	—	ps
$Z_{TX\_DIFF\_DC}$	Differential impedance		80	100	120	Ohms
J_{TX_DDJ}[3, 4, 5]	Output data deterministic jitter		—	—	0.10	UI
J_{TX_TJ}[2, 3, 4, 5]	Total output data jitter		—	—	0.24	UI

1. Rise and fall times measured with board trace, connector and approximately 2.5pf load.
2. Total jitter includes both deterministic jitter and random jitter. The random jitter is the total jitter minus the actual deterministic jitter.
3. Jitter values are measured with each CML output AC coupled into a 50-ohm impedance (100-ohm differential impedance).
4. Jitter and skew are specified between differential crossings of the 50% threshold of the reference signal.
5. Values are measured at 1.25 Gbps.

Table 3-18. Receive and Jitter Tolerance

Symbol	Description	Test Conditions	Min.	Typ.	Max.	Units
RL_{RX_DIFF}	Differential return loss	From 100 MHz to 1.25 GHz	10	—	—	dB
RL_{RX_CM}	Common mode return loss	From 100 MHz to 1.25 GHz	6	—	—	dB
Z_{RX_DIFF}	Differential termination resistance		80	100	120	Ohms
J_{RX_DJ}[1, 2, 3, 4, 5]	Deterministic jitter tolerance (peak-to-peak)		—	—	0.34	UI
J_{RX_RJ}[1, 2, 3, 4, 5]	Random jitter tolerance (peak-to-peak)		—	—	0.26	UI
J_{RX_SJ}[1, 2, 3, 4, 5]	Sinusoidal jitter tolerance (peak-to-peak)		—	—	0.11	UI
J_{RX_TJ}[1, 2, 3, 4, 5]	Total jitter tolerance (peak-to-peak)		—	—	0.71	UI
T_{RX_EYE}	Receiver eye opening		0.29	—	—	UI

1. Total jitter includes deterministic jitter, random jitter and sinusoidal jitter. The sinusoidal jitter tolerance mask is shown in Figure 3-14.
2. Jitter values are measured with each high-speed input AC coupled into a 50-ohm impedance.
3. Jitter and skew are specified between differential crossings of the 50% threshold of the reference signal.
4. Jitter tolerance, Differential Input Sensitivity and Receiver Eye Opening parameters are characterized when Full Rx Equalization is enabled.
5. Values are measured at 1.25 Gbps.

HDMI (High-Definition Multimedia Interface) Electrical and Timing Characteristics

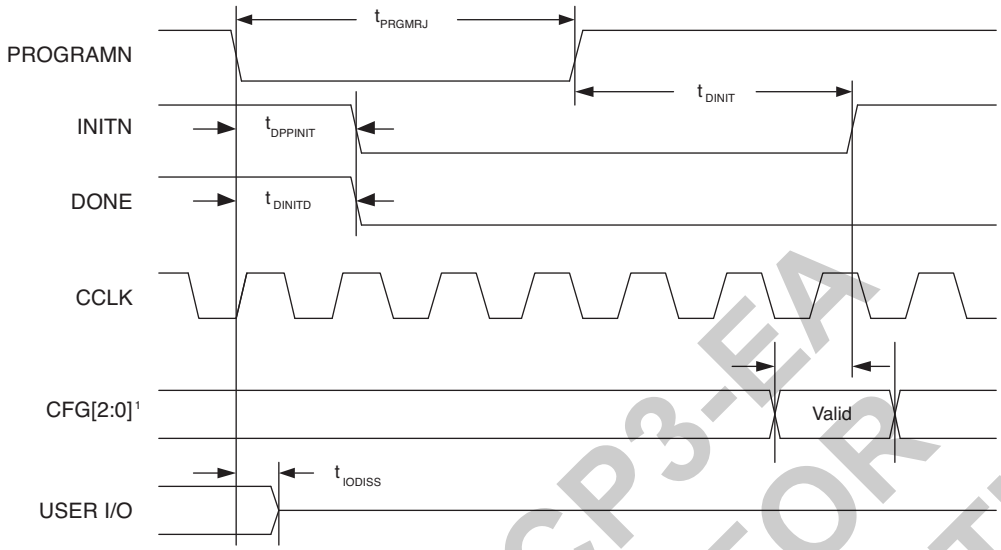
AC and DC Characteristics

Table 3-22. Transmit and Receive[1, 2]

Symbol	Description	Spec. Compliance		Units
		Min. Spec.	Max. Spec.	
Transmit				
Intra-pair Skew		—	75	ps
Inter-pair Skew		—	800	ps
TMDS Differential Clock Jitter		—	0.25	UI
Receive				
R_T	Termination Resistance	40	60	Ohms
V_{ICM}	Input AC Common Mode Voltage (50-ohm Setting)	—	50	mV
TMDS Clock Jitter	Clock Jitter Tolerance	—	0.25	UI

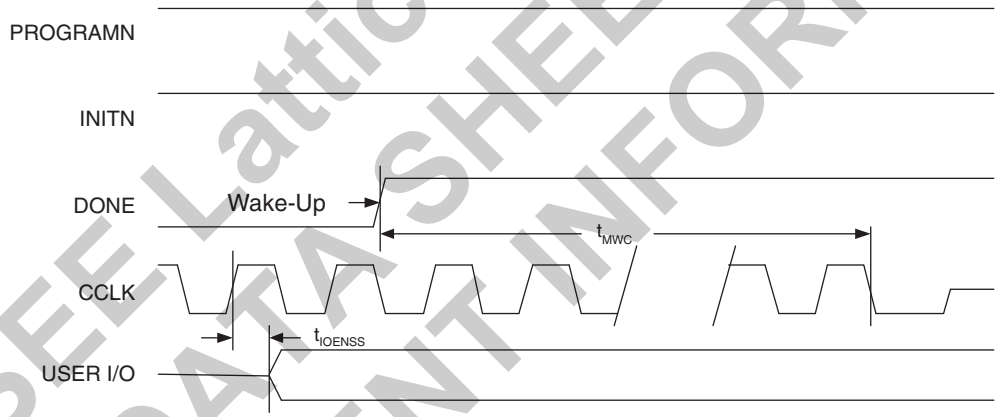
1. Output buffers must drive a translation device. Max. speed is 2Gbps. If translation device does not modify rise/fall time, the maximum speed is 1.5Gbps.
2. Input buffers must be AC coupled in order to support the 3.3V common mode. Generally, HDMI inputs are terminated by an external cable equalizer before data/clock is forwarded to the LatticeECP3 device.

Figure 3-22. Configuration from PROGRAMN Timing



1. The CFG pins are normally static (hard wired)

Figure 3-23. Wake-Up Timing

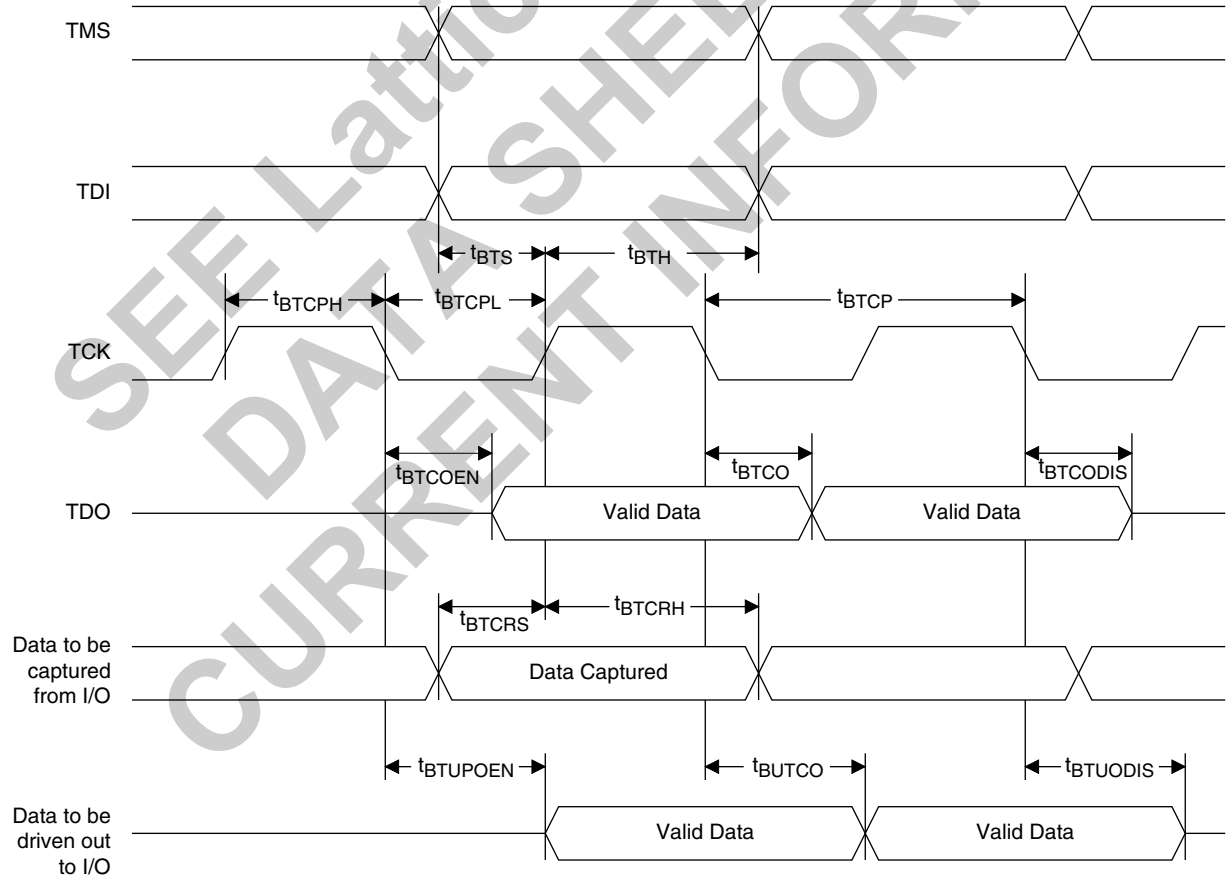


JTAG Port Timing Specifications

Over Recommended Operating Conditions

Symbol	Parameter	Min	Max	Units
f_{MAX}	TCK clock frequency	—	25	MHz
t_{BTCP}	TCK [BSCAN] clock pulse width	40	—	ns
t_{BTCPH}	TCK [BSCAN] clock pulse width high	20	—	ns
t_{BTCPL}	TCK [BSCAN] clock pulse width low	20	—	ns
t_{BTS}	TCK [BSCAN] setup time	10	—	ns
t_{BTH}	TCK [BSCAN] hold time	8	—	ns
t_{BTRF}	TCK [BSCAN] rise/fall time	50	—	mV/ns
t_{BTCO}	TAP controller falling edge of clock to valid output	—	10	ns
$t_{BTCODIS}$	TAP controller falling edge of clock to valid disable	—	10	ns
t_{BTCOEN}	TAP controller falling edge of clock to valid enable	—	10	ns
t_{BTCRS}	BSCAN test capture register setup time	8	—	ns
t_{BTCRH}	BSCAN test capture register hold time	25	—	ns
t_{BUTCO}	BSCAN test update register, falling edge of clock to valid output	—	25	ns
$t_{BTUODIS}$	BSCAN test update register, falling edge of clock to valid disable	—	25	ns
$t_{BTUPOEN}$	BSCAN test update register, falling edge of clock to valid enable	—	25	ns

Figure 3-25. JTAG Port Timing Waveforms



Signal Descriptions (Cont.)

Signal Name	I/O	Description
D7/SPID0	I/O	Parallel configuration I/O. SPI/SPIm data input. Open drain during configuration.
DI/CSSPI0N/CEN	I/O	Serial data input for slave serial mode. SPI/SPIm mode chip select.
Dedicated SERDES Signals[2]		
PCS[Index]_HDINNm	I	High-speed input, negative channel m
PCS[Index]_HDOUTNm	O	High-speed output, negative channel m
PCS[Index]_REFCLKN	I	Negative Reference Clock Input
PCS[Index]_HDINPm	I	High-speed input, positive channel m
PCS[Index]_HDOUTPm	O	High-speed output, positive channel m
PCS[Index]_REFCLKP	I	Positive Reference Clock Input
PCS[Index]_VCCOBm	—	Output buffer power supply, channel m (1.2V/1.5)
PCS[Index]_VCCIBm	—	Input buffer power supply, channel m (1.2V/1.5V)

1. When placing switching I/Os around these critical pins that are designed to supply the device with the proper reference or supply voltage, care must be given.
2. m defines the associated channel in the quad.

Pin Information Summary (Cont.)

Pin Information Summary		ECP3-17EA		ECP3-35EA		
Pin Type		256 ftBGA	484 fpBGA	256 ftBGA	484 fpBGA	672 fpBGA
Emulated Differential I/O per Bank	Bank 0	13	18	13	21	24
	Bank 1	7	12	7	18	18
	Bank 2	2	4	1	8	8
	Bank 3	4	13	5	20	19
	Bank 6	5	13	6	22	20
	Bank 7	6	10	6	11	13
	Bank 8	12	12	12	12	12
Highspeed Differential I/O per Bank	Bank 0	0	0	0	0	0
	Bank 1	0	0	0	0	0
	Bank 2	2	3	3	6	6
	Bank 3	5	9	4	9	12
	Bank 6	5	9	4	11	12
	Bank 7	5	8	5	9	10
	Bank 8	0	0	0	0	0
Total Single Ended/ Total Differential I/O per Bank	Bank 0	26/13	36/18	26/13	42/21	48/24
	Bank 1	14/7	24/12	14/7	36/18	36/18
	Bank 2	8/4	14/7	8/4	28/14	28/14
	Bank 3	18/9	44/22	18/9	58/29	63/31
	Bank 6	20/10	44/22	20/10	67/33	65/32
	Bank 7	23/11	36/18	23/11	40/20	46/23
	Bank 8	24/12	24/12	24/12	24/12	24/12
DDR Groups Bonded per Bank	Bank 0	2	3	2	3	4
	Bank 1	1	2	1	3	3
	Bank 2	0	1	0	2	2
	Bank 3	1	3	1	3	4
	Bank 6	1	3	1	4	4
	Bank 7	1	2	1	3	3
	Configuration Bank 8	0	0	0	0	0
SERDES Quads		1	1	1	1	1

1. These pins must remain floating on the board.

Pin Information Summary (Cont.)

Pin Information Summary		ECP3-95E			ECP3-95EA			ECP3-150EA	
Pin Type		484 fpBGA	672 fpBGA	1156 fpBGA	484 fpBGA	672 fpBGA	1156 fpBGA	672 fpBGA	1156 fpBGA
Emulated Differential I/O per Bank	Bank 0	21	30	43	21	30	43	30	47
	Bank 1	18	24	39	18	24	39	24	43
	Bank 2	10	15	16	8	12	13	12	18
	Bank 3	23	27	39	20	23	33	23	37
	Bank 6	26	30	39	22	25	33	25	37
	Bank 7	14	20	22	11	16	18	16	24
	Bank 8	12	12	12	12	12	12	12	12
Highspeed Differential I/O per Bank	Bank 0	0	0	0	0	0	0	0	0
	Bank 1	0	0	0	0	0	0	0	0
	Bank 2	4	6	6	6	9	9	9	15
	Bank 3	6	8	10	9	12	16	12	21
	Bank 6	7	9	10	11	14	16	14	21
	Bank 7	6	8	9	9	12	13	12	18
	Bank 8	0	0	0	0	0	0	0	0
Total Single Ended/ Total Differential I/O per Bank	Bank 0	42/21	60/30	86/43	42/21	60/30	86/43	60/30	94/47
	Bank 1	36/18	48/24	78/39	36/18	48/24	78/39	48/24	86/43
	Bank 2	28/14	42/21	44/22	28/14	42/21	44/22	42/21	66/33
	Bank 3	58/29	71/35	98/49	58/29	71/35	98/49	71/35	116/58
	Bank 6	67/33	78/39	98/49	67/33	78/39	98/49	78/39	116/58
	Bank 7	40/20	56/28	62/31	40/20	56/28	62/31	56/28	84/42
	Bank 8	24/12	24/12	24/12	24/12	24/12	24/12	24/12	24/12
DDR Groups Bonded per Bank	Bank 0	3	5	7	3	5	7	5	7
	Bank 1	3	4	7	3	4	7	4	7
	Bank 2	2	3	3	2	3	3	3	4
	Bank 3	3	4	5	3	4	5	4	7
	Bank 6	4	4	5	4	4	5	4	7
	Bank 7	3	4	4	3	4	4	4	6
	Configuration Bank8	0	0	0	0	0	0	0	0
SERDES Quads		1	2	3	1	2	3	2	4

1.These pins must remain floating on the board.

LatticeECP3 Family Data Sheet Revision History

Date	Version	Section	Change Summary
February 2009	01.0	—	Initial release.
May 2009	01.1	All	Removed references to Parallel burst mode Flash.
		Introduction	Features - Changed 250 Mbps to 230 Mbps in Embedded SERDES bulleted section and added a footnote to indicate 230 Mbps applies to 8b10b and 10b12b applications.
			Updated data for ECP3-17 in LatticeECP3 Family Selection Guide table.
			Changed embedded memory from 552 to 700 Kbits in LatticeECP3 Family Selection Guide table.
		Architecture	Updated description for CLKFB in General Purpose PLL Diagram.
			Corrected Primary Clock Sources text section.
			Corrected Secondary Clock/Control Sources text section.
			Corrected Secondary Clock Regions table.
			Corrected note below Detailed sysDSP Slice Diagram.
			Corrected Clock, Clock Enable, and Reset Resources text section.
			Corrected ECP3-17 EBR number in Embedded SRAM in the LatticeECP3 Family table.
			Added On-Chip Termination Options for Input Modes table.
			Updated Available SERDES Quads per LatticeECP3 Devices table.
			Updated Simplified Channel Block Diagram for SERDES/PCS Block diagram.
			Updated Device Configuration text section.
			Corrected software default value of MCLK to be 2.5 MHz.
		DC and Switching Characteristics	Updated VCCOB Min/Max data in Recommended Operating Conditions table.
			Corrected footnote 2 in sysIO Recommended Operating Conditions table.
			Added added footnote 7 for t_{SKEW_PRIB} to External Switching Characteristics table.
			Added 2-to-1 Gearing text section and table.
			Updated External Reference Clock Specification (refclkp/refclkn) table.
			LatticeECP3 sysCONFIG Port Timing Specifications - updated t_{DINIT} information.
			Added sysCONFIG Port Timing waveform.
			Serial Input Data Specifications table, delete Typ data for $V_{RX\text{-}DIFF\text{-}S}$.
			Added footnote 4 to sysCLOCK PLL Timing table for t_{PFD}.
			Added SERDES/PCS Block Latency Breakdown table.
			External Reference Clock Specifications table, added footnote 4, add symbol name vREF-IN-DIFF.
			Added SERDES External Reference Clock Waveforms.
			Updated Serial Output Timing and Levels table.
			Pin-to-pin performance table, changed "typically 3% slower" to "typically slower".